

Notice of References Cited	Application/Control No. 10/695,197	Applicant(s)/Patent Under Reexamination FUJIYAMA ET AL.	
	Examiner Nguyen T. Ha	Art Unit 2831	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,593,535	07-2003	Gailus, Mark W.	174/262
	C	US-6,384,341	05-2002	Rothermel et al.	174/255
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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